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PERFORMANCE CHECKSHEET

Model: AVR-EB4-B-NXPB-SOD123W  
Type: Semiconductor Device Tester  
S.N.: 14536  
Date: March 10, 2025

Output Amplitude: to +0.5A, -1A  
Pulse Width (FWHM): 2 us (-)  
Switching time (10%-90%):  
≤ 1.5 ns typically  
PRF: 1 Hz - 1 kHz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

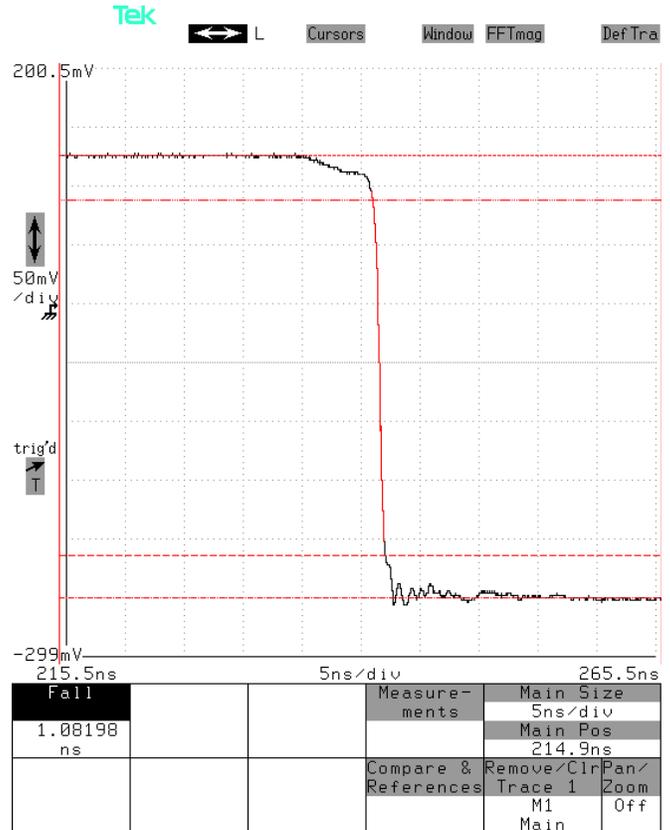
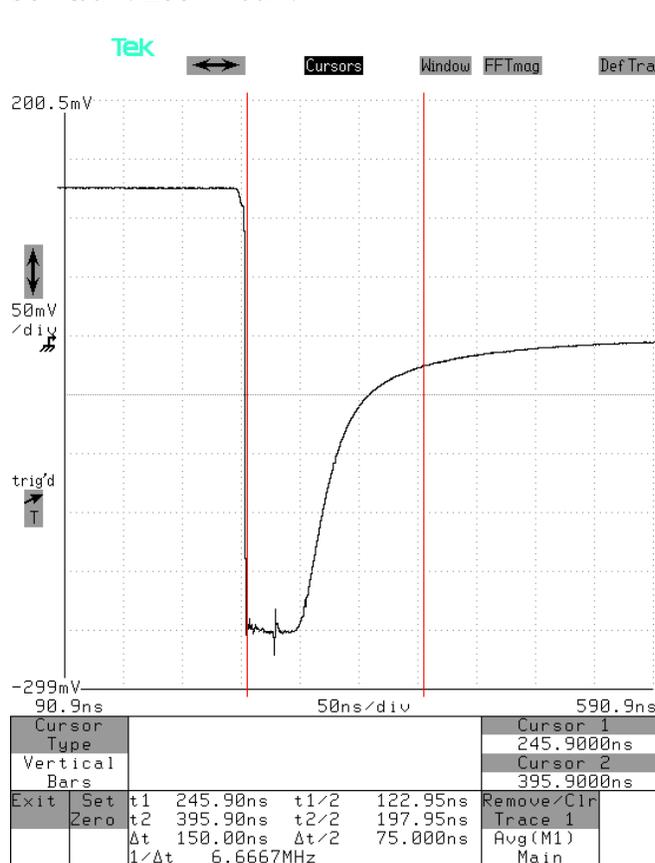
Test Waveforms

Reverse recovery transient of 1N4937 at +0.5A and -1A, using the AVX-TRR-NXPB-MIX test jig (S/N 14538)

As before, but scaled to show the sub-nanosecond switching time.

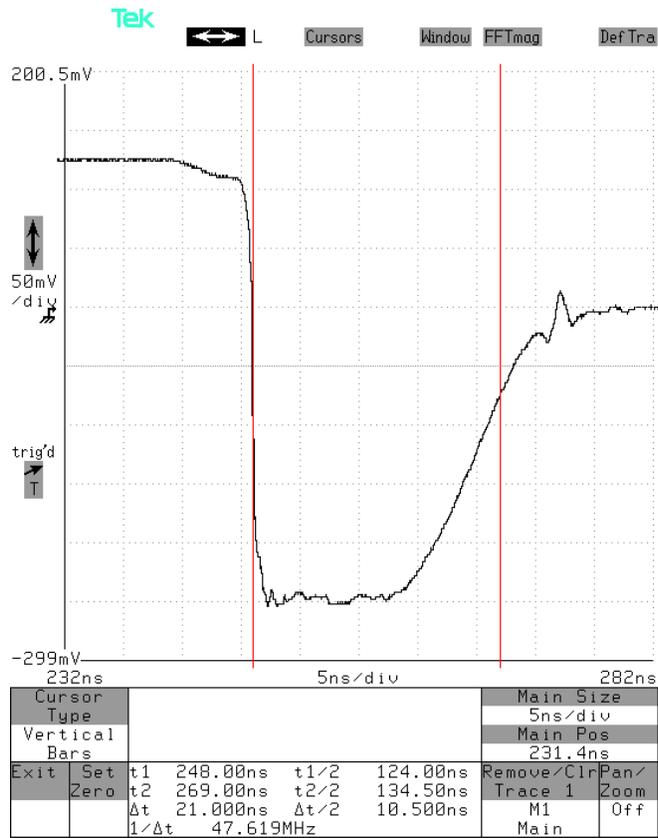
50 ns/div. 200 mA/div:

5 ns/div. 200 mA/div:



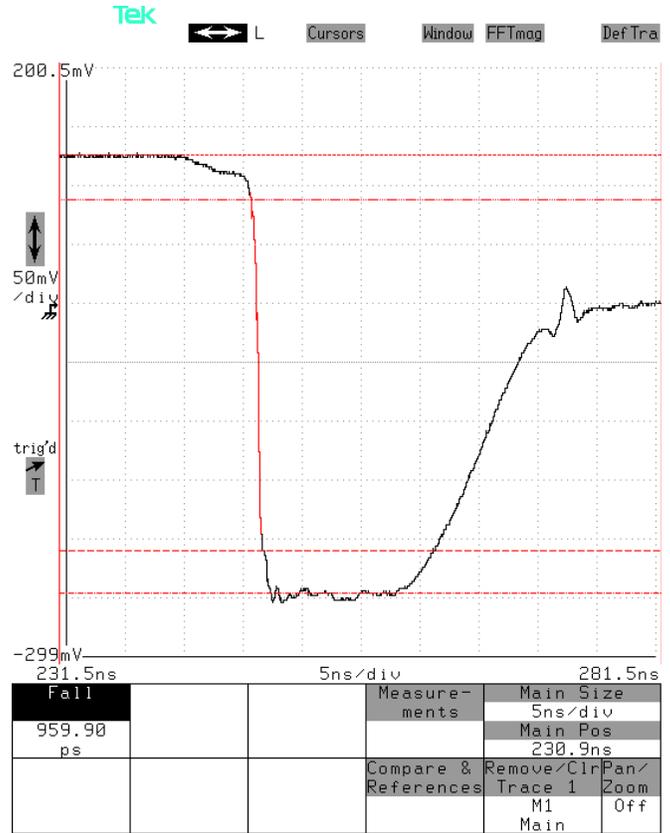
Reverse recovery transient of Central Semi CMMR1S-02 at +0.5A and -1A (using voltage amplitudes of +107V and -83V), with recovery measured to -0.25A, using the AVX-TRR-NXPB-SOD123W test jig (S/N 14536). The measured  $t_{RR}$  is 21 ns (meeting the datasheet specification of < 35 ns).

5 ns/div. 200 mA/div:



Same waveform, but showing the pulse + to - switching time.

5 ns/div. 200 mA/div:



Reverse recovery transient of a PMEG6045ETPX at +0.5A and -0.5A (using voltage amplitudes of +107V and -53V), with recovery time measured at -0.1A, using the AVX-TRR-NXPB-SOD128 test jig (S/N 14537). The measured  $t_{RR}$  is 17.5 ns (meeting the datasheet specification of < 20 ns).

5 ns/div. 200 mA/div:

